

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
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	Examiner	Art Unit	Page 1 of 1
	Rip A. Lee	1713	

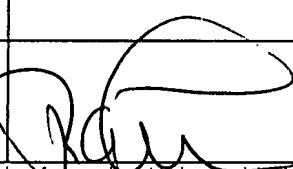
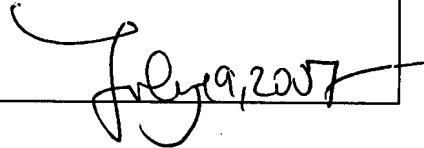
**U.S. PATENT DOCUMENTS**

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*	A	US-4,491,621	01-1985	Okumoto et al.	428/519
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*	C	US-5,852,093	12-1998	Aimura et al.	524/432
*	D	US-2003/0127803	07-2003	Yokoyama et al.	277/549
*	E	US-4,278,587	07-1981	Wolff et al.	524/262
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N	JP 2000-317951	11-2000	Japan	Haga	B29C 35/02
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	JP 2000-317951 (abstract and translation in English)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.